

## SLOVENSKI STANDARD SIST ISO 12233:2017

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Nadomešča: SIST ISO 12233:2014

# Fotografija - Elektronsko prikazovanje mirujočih slik - Resolucija (ločljivost) in frekvenčni odzivi v prostoru

Photography - Electronic still picture imaging - Resolution and spatial frequency responses

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Photographie - Imagerie des prises de vues électroniques - Résolution et réponses en fréquence spatiale SIST ISO 12233:2017 https://standards.iteh.ai/catalog/standards/sist/35b02e6d-357f-40f1-b63f-

2a997d6cf727/sist-iso-12233-2017

Ta slovenski standard je istoveten z: ISO 12233:2017

### <u>ICS:</u>

37.040.10 Fotografska oprema. Projektorji

Photographic equipment. Projectors

SIST ISO 12233:2017

en,fr

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#### SIST ISO 12233:2017

# INTERNATIONAL STANDARD

ISO 12233

Third edition 2017-01

## Photography — Electronic still picture imaging — Resolution and spatial frequency responses

Photographie — Imagerie des prises de vues électroniques — Résolution et réponses en fréquence spatiale

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Reference number ISO 12233:2017(E)

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### Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular the different approval criteria needed for the different types of ISO documents should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see <a href="https://www.iso.org/directives">www.iso.org/directives</a>).

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. ISO shall not be held responsible for identifying any or all such patent rights. Details of any patent rights identified during the development of the document will be in the Introduction and/or on the ISO list of patent declarations received (see <a href="https://www.iso.org/patents">www.iso.org/patents</a>).

Any trade name used in this document is information given for the convenience of users and does not constitute an endorsement.

For an explanation on the meaning of ISO specific terms and expressions related to conformity assessment, as well as information about ISO's adherence to the World Trade Organization (WTO) principles in the Technical Barriers to Trade (TBT) see the following URL: www.iso.org/iso/foreword.html.

The committee responsible for this document is ISO/TC 42, *Photography*.

This third edition cancels and replaces the second edition (ISO 12233:2014), of which it constitutes a minor revision with thanges and Amnex Dalog/standards/sist/35b02e6d-357f-40fl-b63f-2a997d6cf727/sist-iso-12233-2017

### Introduction

#### Purpose

The spatial resolution capability is an important attribute of an electronic still-picture camera. Resolution measurement standards allow users to compare and verify spatial resolution measurements. This document defines terminology, test charts, and test methods for performing resolution measurements for analogue and digital electronic still-picture cameras.

#### Technical background

For consumer digital cameras, the term *resolution* is often incorrectly interpreted as the number of addressable photoelements. While there are existing protocols for determining camera pixel counts, these are not to be confused with the interpretation of resolution as addressed in this document. Qualitatively, resolution is the ability of a camera to optically capture finely spaced detail, and is usually reported as a single valued metric. Spatial frequency response (SFR) is a multi-valued metric that measures contrast loss as a function of spatial frequency. Generally, contrast decreases as a function of spatial frequency to a level where detail is no longer visually resolved. This limiting frequency value is the resolution of the camera. A camera's resolution and its SFR are determined by a number of factors. These include, but are not limited to, the performance of the camera lens, the number of addressable photoelements in the optical imaging device, and the electrical circuits in the camera, which can include image compression and gamma correction functions.

While resolution and SFR are related metrics, their difference lies in their comprehensiveness and utility. As articulated in this document, resolution is a single frequency parameter that indicates whether the output signal contains a minimum threshold of detail information for visual detection. In other words, resolution is the highest spatial frequency that a candidate camera can usefully capture under cited conditions. It can be very valuable for rapid manufacturing testing, quality control monitoring, or for providing a simple metric that can be easily understood by end users. The algorithm used to determine resolution has been tested with visual experiments using human observers and correlates well with their estimation of high frequency detail loss released and resolutions.

SFR is a numerical description of how contrast is changed by a camera as a function of the spatial frequencies that describe the contrast. It is very beneficial for engineering, diagnostic, and image evaluation purposes and serves as an umbrella function from which such metrics as sharpness and acutance are derived. Often, practitioners will select the spatial frequency associated with a specified SFR level as a modified non-visual resolution value.

In a departure from the first edition of this document, two SFR measurements are described. Additionally, the first SFR metrology method, edge-based spatial frequency response, is identical to that described in the first edition, except that a lower contrast edge is used for the test chart. Regions of interest (ROI) near slanted vertical and horizontal edges are digitized and used to compute the SFR levels. The use of a slanted edge allows the edge gradient to be measured at many phases relative to the image sensor photoelements and to yield a phase-averaged SFR response.

A second sine wave-based SFR metrology technique is introduced in the second edition. Using a sine wave modulated target in a polar format (e.g. Siemens star), it is intended to provide an SFR response that is more resilient to ill-behaved spatial frequency signatures introduced by the image content driven processing of consumer digital cameras. In this sense, it is intended to enable easier interpretation of SFR levels from such camera sources. Comparing the results of the edge-based SFR and the sine-based SFR might indicate the extent to which nonlinear processing is used.

The first step in determining visual resolution or SFR is to capture an image of a suitable test chart with the camera under test. The test chart should include features of sufficiently fine detail and frequency content such as edges, lines, square waves, or sine wave patterns. The test chart defined in this document has been designed specifically to evaluate electronic still-picture cameras. It has not necessarily been designed to evaluate other electronic imaging equipment such as input scanners, CRT displays, hard-copy printers, or electro-photographic copiers, nor individual components of an electronic still-picture camera, such as the lens.

Some of the measurements described in this document are performed using digital analysis techniques. They are also applicable with the analogue outputs of the camera by digitizing the analogue signals if there is adequate digitizing equipment.

#### Methods for measuring SFR and resolution — Selection rationale and guidance

This section is intended to provide more detailed rationale and guidance for the selection of the different resolution metrology methods presented in this document. While resolution metrology of analogue optical systems, by way of spatial frequency response, is well established and largely consistent between methodologies (e.g. sine waves, lines, edges), metrology data for such systems are normally captured under well-controlled conditions where the required data linearity and spatial isotropy assumptions hold. Generally, it is not safe to assume these conditions for files from many digital cameras, even under laboratory capture environments. Exposure and image content dependent image processing of the digital image file before it is provided as a finished file to the user prevents this. This processing yields different SFR responses depending on the features in the scene or in the case of this document, the target. For instance, in-camera edge detection algorithms might specifically operate on edge features and selectively enhance or blur them based on complex nonlinear decision rules. Depending on the intent, these algorithms might also be tuned differently for repetitive scene features such as those found in sine waves or bar pattern targets. Even for constrained camera settings recommended in this document, these nonlinear operators can yield differing SFR results depending on the target feature set. Naturally, this causes confusion on which targets to use, either alone or in combination. Guidelines for selection are offered below.

Edges are common features in naturally occurring scenes. They also tend to act as visual acuity cues by which image quality is judged and imaging artefacts are manifested. This logic prescribed their use for SFR metrology in the past and current editions of this document. It is also why edge features are prone to image processing in many consumer digital cameras: they are visually important. All other imaging conditions being equal, camera SFRs using different target contrast edge features can be significantly different, especially with respect to their morphology. This is largely due to nonlinear image processing operators and would not occur for strictly linear imaging systems. To moderate this behaviour, a lower contrast slanted edge feature (Figure Ch) was chosen to replace the higher contrast version of the first edition. This feature choice still allows for acuity-amenable SFR results beyond the half-sampling frequency and helps prevent nonlinear data clipping that can occur with high contrast target features. It is also a more reliable rendering of visually important contrast levels in naturally occurring scenes.

Sine wave features have long been the choice for directly calculating SFR of analogue imaging systems and they are intuitively satisfying. They have been introduced into the second edition based on experiences from the edge-based approach. Because sine waves transition more slowly than edges, they are not prone to being identified as edges in embedded camera processors. As such, the ambiguity that image processing imposes on the SFR can be largely avoided by their use. Alternatively, if the image processing is influenced by the absence of sharp features, more aggressive processing might be used by the camera. A sine wave starburst test pattern (Figure 6) is adopted in the second edition. With the appropriate analysis software, a sine wave-based SFR can be calculated up to the half-sampling frequency. For the same reasons stated above, the sine wave-based target is also of low contrast and consistent with that of the edge-based version. An added benefit of the target's design over other sine targets is its compactness and bi-directional features.

All experience suggests that there is no single SFR for today's digital cameras. Even under the strict capture constraints suggested in this document, the allowable feature sets that most digital cameras offer prevent such unique characterization. Confusion can be reduced through complete documentation of the capture conditions and camera setting for which the SFR was calculated. It has been suggested that comparing edge-based and sine wave-based SFR results under the same capture conditions could be a good tool in assessing the contribution of spatial image processing in digital cameras.

Finally, at times, a full SFR characterization is simply not required, such as in end of line camera assembly testing. Alternately, SFR might be an intimidating obstacle to those not trained in its utility. For those in need of a simple and intuitive space domain approach to resolution using repeating line patterns, a visual resolution metric is also provided in this third edition of this document.

With such a variety of methods available for measuring resolution, there are bound to be differences in measured resolution results. To benchmark the likely variations, the committee has published the results of a pilot study using all of the proposed techniques and how they relate to each other. These results are provided in Reference [20].

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## Photography — Electronic still picture imaging — Resolution and spatial frequency responses

### 1 Scope

This document specifies methods for measuring the resolution and the SFR of electronic still-picture cameras. It is applicable to the measurement of both monochrome and colour cameras which output digital data or analogue video signals.

#### 2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

ISO 14524, Photography — Electronic still-picture cameras — Methods for measuring opto-electronic conversion functions (OECFs)

## 3 Terms and definitions TANDARD PREVIEW

For the purposes of this document, the following terms and definitions apply.

ISO and IEC maintain terminological databases for use in standardization at the following addresses: <u>SIST ISO 12233:2017</u>

- IEC Electropedia:payailable.at.http://www.electropedia.org/57f-40fl-b63f-
- 2a997d6cf727/sist-iso-12233-2017
  ISO Online browsing platform: available at <a href="http://www.iso.org/obp">http://www.iso.org/obp</a>

#### 3.1

#### addressable photoelements

number of active photoelements in an *image sensor* (3.11)

Note 1 to entry: This equals the product of the number of active photoelement lines and the number of active photoelements per line.

#### 3.2

#### aliasing

output image artefacts that occur in a *sampled imaging system* (3.23) due to insufficient sampling

Note 1 to entry: These artefacts usually manifest themselves as moiré patterns in repetitive image features or as jagged stair-stepping at edge transitions.

#### 3.3 cycles per millimetre

### cy/mm

spatial frequency unit defined as the number of spatial periods per millimetre

#### 3.4

### edge spread function

ESF

normalized spatial signal distribution in the *linearized* (<u>3.15</u>) output of an imaging system resulting from imaging a theoretical infinitely sharp edge

#### 3.5

#### effectively spectrally neutral

having spectral characteristics which result in a specific imaging system producing the same output as for a *spectrally neutral* (3.25) object

#### 3.6

#### electronic still-picture camera

camera incorporating an *image sensor* (3.11) that outputs an analogue or digital signal representing a still picture

Note 1 to entry: This camera may also record or store an analogue or digital signal representing a still picture on a removable media, such as a memory card or magnetic disc.

#### 3.7

#### gamma correction

signal processing operation that changes the relative signal levels

Note 1 to entry: Gamma correction is performed, in part, to correct for the nonlinear light output versus signal input characteristics of the display. The relationship between the light input level and the output signal level, called the camera opto-electronic conversion function (OECF), provides the gamma correction curve shape for an image capture device.

Note 2 to entry: The gamma correction is usually an algorithm, lookup table, or circuit which operates separately on each colour component of an image.

#### 3.8

## horizontal resolution iTeh STANDARD PREVIEW

*resolution* (3.22) value measured in the longer image dimension, corresponding to the horizontal direction for a "landscape" image orientation. typically using a vertical or near vertical oriented test-chart feature

#### 3.9

#### image aspect ratio

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ratio of the image width to the image height

#### 3.10

#### image compression

process that alters the way digital image data are encoded to reduce the size of an image file

#### 3.11

#### image sensor

electronic device that converts incident electromagnetic radiation into an electronic signal

EXAMPLE Charge coupled device (CCD) array, complementary metal-oxide semiconductor (CMOS) array.

#### 3.12

#### line pairs per millimetre

lp/mm

spatial frequency unit defined as the number of equal width black and white line pairs per millimetre

#### 3.13

### line spread function

#### LSF

normalized spatial signal distribution in the *linearized* (3.15) output of an imaging system resulting from imaging a theoretical infinitely thin line

#### 3.14 line widths per picture height LW/PH

spatial frequency unit for specifying the width of a feature on a *test chart* (3.26) relative to the height of the active area of the chart

Note 1 to entry: The value in LW/PH indicates the total number of lines of the same width which can be placed edge to edge within the height of a test target or within the vertical field of view of a camera.

Note 2 to entry: This unit is used whatever the orientation of the "feature" (e.g. line). Specifically, it applies to horizontal, vertical, and diagonal lines.

EXAMPLE If the height of the active area of the chart equals 20 cm, a black line of 1 000 LW/PH has a width equal to 20/1 000 cm.

#### 3.15

#### linearized

digital signal conversion performed to invert the camera opto-electronic conversion function (OECF) to focal plane exposure or scene luminance

#### 3.16 lines per millimetre

### lines/mm

spatial frequency unit defined as the number of equal width black and white lines per millimetre

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Note 1 to entry: One line pair per millimetre (lp/mm) is equal to 2 lines/mm.

#### 3.17

#### modulation

normalized amplitude of signal levels

Note 1 to entry: This is the difference between the minimum and maximum signal levels divided by the average signal level. 2a997d6cf727/sist-iso-12233-2017

#### 3.18 modulation transfer function MTF

modulus of the optical transfer function (3.20)

Note 1 to entry: For the MTF to have significance, it is necessary that the imaging system be operating in an isoplanatic region and in its linear range. Because most *electronic still-picture cameras* (3.6) provide spatial colour sampling and nonlinear processing, a meaningful MTF of the camera can only be approximated through the SFR. See ISO 15529:2010.

#### 3.19

#### normalized spatial frequency

spatial frequency unit for specifying resolution characteristics of an imaging system in terms of cycles per pixel rather than in cycles/millimetre or any other unit of length

#### 3.20 optical transfer function OTF

two-dimensional Fourier transform of the imaging system's *point spread function* (3.21)

Note 1 to entry: For the OTF to have significance, it is necessary that the imaging system be operating in an isoplanatic region and in its linear range. The OTF is a complex function whose modulus has unity value at zero spatial frequency (see ISO 9334). Because most *electronic still-picture cameras* (3.6) provide spatial colour sampling and nonlinear processing, a meaningful OTF of the camera can only be approximated through the SFR.

#### 3.21

### point spread function

#### PSF

normalized spatial signal distribution in the *linearized* (3.15) output of an imaging system resulting from imaging a theoretical infinitely small point source

#### 3.22

#### resolution

measure of the ability of a camera system, or a component of a camera system, to depict picture detail

#### 3.23

#### sampled imaging system

imaging system or device which generates an image signal by sampling an image at an array of discrete points, or along a set of discrete lines, rather than a continuum of points

Note 1 to entry: The sampling at each point is done using a finite-size sampling aperture or area.

#### 3.24

### spatial frequency response

#### SFR

relative amplitude response of an imaging system as a function of input spatial frequency

Note 1 to entry: The SFR is normally represented by a curve of the output response to an input sinusoidal spatial luminance distribution of unit amplitude, over a range of spatial frequencies. The SFR is divided by its value at the spatial frequency of 0 as normalization to yield a value of 1,0 at a spatial frequency of 0.

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#### edge-based spatial frequency response e-SFR (standards.iteh.ai)

measured amplitude response of an imaging system to a slanted-edge input

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Note 1 to entry: Measurement of e/SFRlis as defined in Clause 6/sist/35b02e6d-357f-40f1-b63f-2a997d6cf727/sist-iso-12233-2017

#### 3.24.2

3.24.1

#### sine wave-based spatial frequency response

#### s-SFR

measured amplitude response of an imaging system to a range of sine wave inputs

Note 1 to entry: Measurement of s-SFR is as defined in <u>Clause 7</u>.

#### 3.25

#### spectrally neutral

exhibiting reflective or transmissive characteristics which are constant over the wavelength range of interest

#### 3.26

#### test chart

arrangement of *test patterns* (3.27) designed to test particular aspects of an imaging system

#### 3.27

#### test pattern

specified arrangement of spectral reflectance or transmittance characteristics used in measuring an image quality attribute

#### 3.27.1

#### bi-tonal pattern

pattern that is *spectrally neutral* (3.25) or *effectively spectrally neutral* (3.5), and consists exclusively of two reflectance or transmittance values in a prescribed spatial arrangement

Note 1 to entry: Bi-tonal patterns are typically used to measure *resolution* (3.22) by visual resolution method.

### 3.27.2

#### hyperbolic wedge test pattern

*bi-tonal pattern* (3.27.1) that varies continuously and linearly with spatial frequency

Note 1 to entry: A bi-tonal hyperbolic wedge test pattern is used to measure *resolution* (3.22) by the visual resolution method in this document.

#### 3.28

#### vertical resolution

*resolution* (3.22) value measured in the shorter image dimension, corresponding to the vertical direction for a "landscape" image orientation, typically using a horizontal or near horizontal oriented test-chart feature

#### 3.29

#### visual resolution

spatial frequency at which all of the individual black and white lines of a test pattern frequency can no longer be distinguished by a human observer

Note 1 to entry: This presumes the features are reproduced on a display or print.

#### 4 Test conditions

#### 4.1 Test chart illumination

The luminance of the **test chart shall be sufficient to provide an acceptable** camera output signal level. The test chart shall be uniformly illuminated as shown in Figure 1, so that the illuminance at the chart is within ±10 % of the illuminance in the centre of the chart at any position within the chart. The illumination sources should be baffled to prevent direct illumination of the camera lens by the illumination sources. The area surrounding the test chart should be of low reflectance to minimize flare light. The chart should be shielded from any reflected light. The jlluminated test chart shall be effectively spectrally neutral within the visible wavelengths. 7

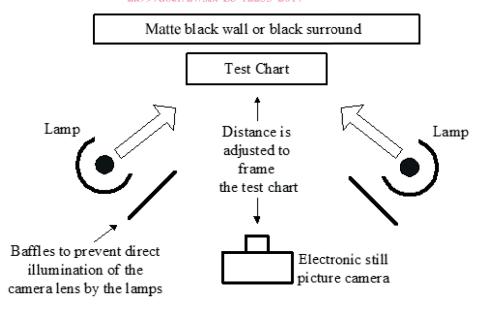


Figure 1 — Test chart illumination method

#### 4.2 Camera framing and lens focal length setting

The camera shall be positioned to properly frame the test target. The vertical framing arrows are used to adjust the magnification and the horizontal arrows are used to centre the target horizontally. The